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Liwei Zhou

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Contents

xi	<i>Symposium Committees</i>
xv	<i>Introduction</i>
6624 02	Simultaneous 360 degree viewing optical system with the lenses of the compound eyes from the dragonfly [6624-01] S.-W. Kim, R. S. Ramakrishna, Gwangju Institute of Science and Technology (South Korea)
6624 03	Evaluating the viscoelastic properties of glass above transition temperature for numerical modeling of lens molding process [6624-02] T. Zhou, J. Yan, T. Kuriyagawa, Tohoku Univ. (Japan)
6624 04	Cobalt chloride doped polymer film for relative humidity measurement [6624-03] P. Nath, M. Datta, A. Barik, A. Ali, H. K. Singh, Gauhati Univ. (India); A. K. Kalita, Assam Engineering College (India); P. Datta, Gauhati Univ. (India)
6624 05	Preexposure effect on the fabrication of continuous relief microstructure and advanced method [6624-04] D. Wang, C. Luo, H. Liu, Z. Ye, Lanzhou Institute of Physics (China)
6624 06	Research on the NO gas-sensitive effect of long-period fiber gratings coated with film [6624-05] Y. Peng, M. Sun, Dalian Univ. of Technology (China) and Dalian Maritime Univ. (China)
6624 07	The optimization of incoherent fiber laser beam combination [6624-06] J. Xu, S. Zhao, S. Zhan, R. Hou, J. Wu, Y. Li, S. Fang, Air Force Engineering Univ. (China)
6624 08	Laser diode transmitter for laser radar based on FM ranging principles [6624-07] W. Yang, J. Zhao, X. Du, Z. Zeng, Q. Wang, The Academy of Equipment Command & Technology (China)
6624 09	The fractal character of micromirror for metal MEMS optical switch [6624-08] Y. Zhang, Y. Luo, X. Xu, Chongqing Univ. of Posts and Telecommunications (China)
6624 0A	Annular sub-aperture stitching interferometry for testing of large aspherical surfaces [6624-09] X. Wang, L. Wang, Changchun Institute of Optics, Fine Mechanics and Physics (China) and Graduate School of the Chinese Academy of Sciences (China); L. Zheng, Changchun Institute of Optics, Fine Mechanics and Physics (China); W. Deng, Changchun Institute of Optics, Fine Mechanics and Physics (China) and Graduate School of the Chinese Academy of Sciences (China); X. Zhang, Changchun Institute of Optics, Fine Mechanics and Physics (China)
6624 0B	Effect of gaps and piston on image quality for large segmented telescope [6624-10] J. Yan, Y. Wen, X. Yu, X. Zhang, Beijing Institute of Technology (China)

- 6624 0C **Study on optical design of all-reflective Fourier transform imaging spectrometer** [6624-11]
M. Liang, N. Liao, Beijing Institute of Technology (China)
- 6624 0D **Testing the large aperture optical components by the sub-aperture stitching interferometer** [6624-12]
Y. He, Z. Wang, Q. Wang, B. Ji, Nanjing Univ. of Science & Technology (China)
- 6624 0E **Studies on LSPR effect of assembled gold nanoparticles film** [6624-13]
D. Du, X. Hong, Tianjin Univ. (China)
- 6624 0F **A new method of realizing the super light space zoom reflector** [6624-14]
K. Tao, S. Fu, X. Qu, B. Sun, Y. Zhou, Harbin Institute of Technology (China)
- 6624 0G **Optical measuring system for defects of artillery lumen** [6624-15]
W. Zhu, C. Xu, D. Xiao, Beijing Institute of Technology (China)
- 6624 0H **Study on the polarization dependency of diffraction efficiency of perfectly conducting blazed gratings** [6624-16]
S. Li, T. Tang, J. Zhu, Xi'an Jiaotong Univ. (China)
- 6624 0I **Design and research of zoom optic system applied in micro-processing using 248nm KrF excimer laser** [6624-17]
X. Liu, T. Chen, T. Zuo, Beijing Univ. of Technology (China)
- 6624 0J **The theoretical and experimental research on endoscopic confocal imaging system** [6624-18]
H. Ge, Donghua Univ. (China); B. Wang, Shanghai Univ. (China); Q. Ren, Shanghai Jiaotong Univ. (China)
- 6624 0K **New design techniques and alignment methods for CGH-null testing of aspheric surface** [6624-19]
G. Kang, J. Xie, Beijing Institute of Technology (China); Y. Liu, China Precision Engineering Institute for Aircraft Industry (China)
- 6624 0L **Methodology on zoom system design and optimization** [6624-20]
Q. Ding, H. Liu, Luoyang Institute of Electro-optical Equipment (China)
- 6624 0M **Research and application of ergonomics to optical microscope** [6624-21]
X. Jiang, Z. Xiao, J. Zhang, Guilin Univ. of Electronic Technology (China)
- 6624 0N **New method for detecting the piston of segmented mirrors: a modification of the peak ratio technique** [6624-22]
D. Qu, Y. Zhao, L. Dong, R. Chen, Beijing Institute of Technology (China)
- 6624 0O **Sampling pulses with symmetric Mach-Zehnder interferometer optical switch** [6624-23]
Y. Yang, Z. Zheng, Z. Li, Beijing Univ. of Aeronautics and Astronautics (China)
- 6624 0P **Performance analysis of Brillouin optical time domain reflectometer using Golay complementary sequence** [6624-24]
X. Cheng, Y. Li, North China Electric Power Univ. (China)

- 6624 0Q **Estimation of the measurement uncertainty based on quasi Monte-Carlo method in optical measurement** [6624-25]
H. Jing, M. Huang, Y. Zhong, B. Kuang, Guilin Univ. of Electronic Technology (China); X. Jiang, Huazhong Univ. of Science and Technology (China)
- 6624 0R **Golay3 sparse aperture systems designed on a spherical surface** [6624-26]
F. Wu, Soochow Univ. (China) and Changzhou Institute of Technology (China); Q. Wu, Soochow Univ. (China) and Univ. of Science and Technology of Suzhou (China); L. Qian, Soochow Univ. (China)
- 6624 0S **Application of conformal optical design in star sensor** [6624-27]
Y. Li, L. Li, Y. Huang, J. Liu, Beijing Institute of Technology (China)
- 6624 0T **Analysis on the interferogram of a low coherence interferometric system for measuring the dispersion of chirped fiber grating through Fourier spectrometry method** [6624-28]
Q. Chen, Beijing Univ. of Posts and Telecommunications (China) and Beijing Institute of Machinery (China); N. Lu, Beijing Institute of Machinery (China); X. Sang, Beijing Univ. of Posts and Telecommunications (China)
- 6624 0U **Research of the application of low-precision large aperture nonimaging optics in free-space optical communication system** [6624-29]
J. Wang, Beijing Institute of Graphic Communication (China); X. Yu, Beijing Institute of Technology (China)
- 6624 0V **Designed achromatic quarter wave plates of subwavelength grating structure** [6624-30]
J. Zhang, S. Yan, C. Zhou, S. Shen, E. Li, H. Tong, National Univ. of Defense Technology (China)
- 6624 0W **Design of multi-layer diffractive lenses to correct secondary spectrum** [6624-31]
H. Xing, Institute of Optics and Electronics (China) and Graduate School of the Chinese Academy of Sciences (China); W. Lin, Institute of Optics and Electronics (China); J. Feng, Z. Liao, Institute of Optics and Electronics (China) and Graduate School of the Chinese Academy of Sciences (China)
- 6624 0X **Image based measurement for the center position error of micro-sphere in micro-target** [6624-32]
T. Wang, Z. Qiu, J. Wang, B. Wang, Tianjin Univ. (China)
- 6624 0Y **Polarization aberrations caused by fold mirrors in optical systems** [6624-33]
Y. Zhang, Beihang Univ. (China); L. Li, Beijing Institute of Technology (China); H. Zhao, Beihang Univ. (China)
- 6624 0Z **Design of the scanning mode coated glass color difference online detection system** [6624-34]
W. Bi, Y. Zhang, D. Wang, B. Zhang, G. Fu, Yanshan Univ. (China)
- 6624 10 **Beaming of light from metallic surface plasmon polaritons nanostructure** [6624-35]
G. Zhang, J. Liu, C. Hu, F. Sun, X. Su, Beijing Jiaotong Univ. (China)

- 6624 11 **A combination of BIM and BEM for efficiently analyzing optical elements** [6624-36]
F. Sun, J. Liu, G. Zhang, C. Hu, X. Su, Beijing Jiaotong Univ. (China)
- 6624 12 **A novel algorithm of wave front time domain testing** [6624-37]
L. Tang, Q. Hao, Q. Zhu, Beijing Institute of Technology (China)
- 6624 13 **ZnO/Ag/ZnO multilayer films deposited at room temperature** [6624-38]
J. Yan, X. Sun, Y. Zhu, Y. Zhao, Ludong Univ. (China)
- 6624 14 **A convertible aerial camera system integrated with film and CCD image sensor** [6624-39]
L. Yan, S. Zhao, Peking Univ. (China); Z. Lian, Peking Univ. (China) and Beihang Univ. (China)
- 6624 15 **Fiber point diffraction interferometer in measurement of spherical lens** [6624-40]
S. Wu, T. Zhou, J. Lin, L. Chen, L. Nie, D. Sha, Beijing Institute of Technology (China)
- 6624 16 **Design of a compact wide field of view HMD optical system using freeform surfaces** [6624-41]
M. M. Talha, Y. Wang, D. Cheng, J. Chang, Beijing Institute of Technology (China)
- 6624 17 **Form error automatic measurement system based on optical fiber sensing array** [6624-42]
S. Jin, Y. Lv, Q. S. Chen, Beijing Institute of Machinery (China)
- 6624 18 **Closed loop high precision position control system with optical scale** [6624-43]
C. Ge, Univ. of Electric and Scientific Technology of China (China) and Institute of Applied Electronics, China Academy of Engineering Physics (China); Y. Liao, Z. He, Z. Luo, Z. Huang, M. Wan, X. Hu, G. Fan, Institute of Applied Electronics, China Academy of Engineering Physics (China); Z. Liang, Univ. of Electric and Scientific Technology of China (China)
- 6624 19 **Analyses of test glass edge-effect on coatings monitoring** [6624-44]
H. Wang, J. Heng, W. Lu, X. Li, W. Xue, Beijing Institute of Technology (China)
- 6624 1A **Ion beam sputter deposition of zirconia thin films** [6624-45]
W. Jin, Changchun Institute of Optics, Fine Mechanics and Physics (China) and Graduate School of the Chinese Academy of Sciences (China); C. Jin, Changchun Institute of Optics, Fine Mechanics and Physics (China); L. Liu, H. Zhu, Changchun Institute of Optics, Fine Mechanics and Physics (China) and Graduate School of the Chinese Academy of Sciences (China); H. Yang, Changchun Institute of Optics, Fine Mechanics and Physics (China)
- 6624 1B **Optical characteristic of ion beam sputter deposited aluminum thin films** [6624-46]
W. Jin, Changchun Institute of Optics, Fine Mechanics and Physics (China) and Graduate School of the Chinese Academy of Sciences (China); C. Jin, Changchun Institute of Optics, Fine Mechanics and Physics (China); H. Zhu, L. Liu, Changchun Institute of Optics, Fine Mechanics and Physics (China) and Graduate School of the Chinese Academy of Sciences (China); H. Yang, Changchun Institute of Optics, Fine Mechanics and Physics (China)
- 6624 1C **Design of absorbency photometer used in a fully automatic ELISA analyzer** [6624-47]
N. Dong, L. Zhu, M. Dong, Beijing Institute of Machinery (China); S. Niu, Beijing Success Technology Co. Ltd. (China)

- 6624 1D **Fisheye supplementary lens for liquid crystal projector** [6624-48]
Z. Jiang, L. Li, Y. Huang, Beijing Institute of Technology (China)
- 6624 1E **A novel verification device for optical aiming equipments** [6624-49]
Z. Zhu, X. Guo, H. Ding, L. Ding, Xi'an Research Institute of High Technology (China)
- 6624 1F **Optimization control based on hierarchical coordination for a space-based telescope** [6624-50]
B. Guo, Z. Liu, Beijing Institute of Technology (China)
- 6624 1G **The measurement and system error analysis of diopter and optical parallax in optical pointing system** [6624-51]
W. Cao, C. Xue, L. Li, Z. An, Changchun Univ. of Science and Technology (China)
- 6624 1H **The research for EO imaging system simulation** [6624-52]
H. Yang, Nankai Univ. (China); L. Wang, Changchun Institute of Optics, Fine Mechanics and Physics (China) and Graduate School of Chinese Academy of Sciences (China); Z. Fang, Nankai Univ. (China); J. Zhang, Changchun Institute of Optics, Fine Mechanics and Physics (China) and Graduate School of Chinese Academy of Sciences (China); X. Zhang, Changchun Institute of Optics, Fine Mechanics and Physics (China)
- 6624 1I **Application of a high-precision interferometric measuring system as phasing the segmented primary mirrors of the next generation of ground-based telescope** [6624-53]
H. Song, Institute of Optics and Electronics (China) and Graduate School of Chinese Academy of Sciences (China); H. Xian, W. Jiang, C. Rao, Institute of Optics and Electronics (China); J. Huang, Institute of Optics and Electronics (China) and Graduate School of Chinese Academy of Sciences (China)
- 6624 1J **A binary beam-splitter for lidar beam-shaping in laser imaging application** [6624-54]
G. Zheng, S. Li, H. Zhou, Wuhan Univ. (China)
- 6624 1K **Design of an inflatable and deployable space reflecting concentrator** [6624-55]
B. Wang, Z. Yang, B. Mao, T. Zhang, Y. Feng, Beijing Institute of Technology (China)
- 6624 1L **Optical properties of porous anodic alumina films implanted with ZnO nanoparticles** [6624-56]
J. Yan, X. Sun, Y. Zhu, Y. Zhao, Ludong Univ. (China)
- 6624 1M **Hybrid phase-diverse phase retrieval algorithm in wavefront sensing for segmented optics** [6624-57]
H. Mao, X. Wang, D. Zhao, Beijing Institute of Technology (China)
- 6624 1N **Summarize of conformal optics** [6624-58]
N. Zhao, J. Chang, Z. Sun, Y. Wang, Beijing Institute of Technology (China)
- 6624 1O **The preparation of AZO films with RF sputtering** [6624-59]
Z. Yu, J. Xu, W. Xue, X. Li, J. Li, Beijing Institute of Technology (China)
- 6624 1P **The effects of process parameters on the properties of ITO films grown by ion beam-assisted deposition using 90In-10Sn (wt%) alloy** [6624-60]
Z. Yu, L. Xiang, W. Xue, H. Wang, W. Lu, Beijing Institute of Technology (China)

- 6624 1Q **An integrated measurement system for LED thermal, optical, and electrical characteristics** [6624-61]
X. Zou, China Jiliang Univ. (China); X. Zheng, Starspec Optoelectronic Technology Co., Ltd. (China); S. Jin, K. Ni, China Jiliang Univ. (China); H. Zhou, X. He, Starspec Optoelectronic Technology Co., Ltd. (China)
- 6624 1R **Characteristics of the photoinduced current pulses of the optically addressed photorefractive BSO spatial light modulators** [6624-62]
X. Li, W. Hu, H. Jia, J. Zhang, J. Yang, National Univ. of Defense Technology (China)
- 6624 1S **Design of a three field-of-view IR system** [6624-63]
J. Chang, Beijing Institute of Technology (China); Z. Weng, Changchun Institute of Optics, Fine Mechanics and Physics (China); Y. Wang, Beijing Institute of Technology (China); H. Jiang, Changchun Univ. of Science and Technology (China); X. Cong, Changchun Institute of Optics, Fine Mechanics and Physics (China)
- 6624 1T **Compressed infrared mirror-lens system design** [6624-64]
T. Ren, Changchun Univ. of Science and Technology (China); J. Chang, Beijing Institute of Technology (China); Z. Weng, Changchun Institute of Optics, Fine Mechanics and Physics (China); H. Jiang, Changchun Univ. of Science and Technology (China); X. Cong, Changchun Institute of Optics, Fine Mechanics and Physics (China)
- 6624 1U **Superprism structure with linear spatial dispersion based on thin film Gires-Tournois cavity** [6624-65]
W. Lv, D. Zhang, J. Chen, Univ. of Shanghai for Science and Technology (China)
- 6624 1V **Computer-aided alignment for the segmented mirrors of three-mirror optical system** [6624-66]
Y. Huang, L. Li, Beijing Institute of Technology (China)
- 6624 1W **Research on blue emitting BaAl_2S_4 : Eu phosphor layers of TFEL** [6624-67]
Z. Ding, Z. Yu, W. Xue, Beijing Institute of Technology (China)
- 6624 1X **Study on the laser beam transformation and its measurement in laser processing** [6624-68]
R. Ye, Y. Huang, Z. Weng, T. Hu, S. Lin, H. Yan, Z. Wu, Xiamen Univ. (China)
- 6624 1Y **Study of wavefront error and polarization of a side mounted infrared window** [6624-69]
J. Liu, L. Li, X. Hu, X. Yu, Beijing Institute of Technology (China)
- 6624 1Z **Application of virtual optical assembly in research and development of special optical instrument** [6624-70]
Z. Xiao, Z. Sun, Guilin Univ. of Electronic Technology (China)
- 6624 20 **Optical design of a confocal scanning laser ophthalmoscope based on adaptive optics** [6624-71]
J. Lu, Y. Zhang, X. Rao, G. Shi, H. Yang, C. Wang, Institute of Optics and Electronics (China)
- 6624 21 **Contamination effects of oil paint on the space optical system** [6624-72]
C. Lu, Y. Zhou, Y. Sang, Harbin Institute of Technology (China)

- 6624 22 **The design of the CMOS wireless barcode scanner applying optical system based on ZigBee** [6624-73]
Y. Chen, J. Peng, Guilin Univ. of Electronic Technology (China)
- 6624 23 **Design of optical elements for imaging the Earth's plasmasphere** [6624-74]
L. Wang, X. Wang, Changchun Institute of Optics, Fine Mechanics and Physics (China) and Graduate School of Chinese Academy of Sciences (China); B. Chen, Changchun Institute of Optics, Fine Mechanics and Physics (China)
- 6624 24 **Antireflection coatings of broad angle range for ultraviolet band designed by rugate coatings** [6624-75]
G. Peng, J. Yang, S. Chang, H. Yin, J. Yang, National Univ. of Defense Technology (China)
- 6624 25 **Influence of the size dispersion on the emission spectra of the hydrogen passivated Si nanoparticles in SiNx** [6624-76]
W. Ding, Z. Hao, W. Yu, J. Zhang, Y. Li, G. Fu, Hebei Univ. (China)
- 6624 26 **Influence of hydrogen dilution on bonding configurations and optical absorption properties of α -Si/SiNx composite films** [6624-77]
W. Yu, Y. Li, W. Ding, J. Zhang, Y. Yang, G. Fu, Hebei Univ. (China)

Author Index

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Conference 6623: Image Processing

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Conference 6624: Optoelectronic System Design, Manufacturing, and Testing

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Introduction

About 14 years ago, when I organized the first International Symposium on Photoelectronic Detection and Imaging (ISPDl) in 1993 at the Friendship Hotel in Beijing, the symposium was going successfully. At the closing ceremony, I expressed my hope and desire to organize the symposium in China again. This year the day came, as we had a great honor to organize the International Symposium on Photoelectronic Detection and Imaging meeting in Beijing once again. It is truly a great pleasure for us to be able to greet our fellow scientists and experts from a number of countries; and I firmly believe this meeting will be a successful international event in the field of photoelectronic detection and imaging.

The purpose of ISPDl'07 is to provide a forum for the participants to disseminate and exchange ideas and to present up-to-date comprehensive assessments of progress and developments in the field of photoelectronic imaging and detection. To this end it is very gratifying to me that we have been assembled here for an informative exchange of opinions.

Collected in these five volumes of are close to 400 papers accepted for presentation at the symposium, contributed by over 1000 authors from more than 10 countries, including China, Japan, Russia, Germany, Netherland, India, United Kingdom, United States, Italy, and South Korea. These papers cover topics such as photoelectronic imaging, photoelectronic detection, opto-electronic system design, manufacturing and testing, imaging processing, related technology and applications, as well as many other aspects. These proceedings will no doubt benefit not only the participants of this meeting but also our colleagues engaged in research and development. It is sincerely hoped that as a consequence of this meeting research and development in photoelectronic detection and imaging will be promoted, and international cooperation between scientists and engineers who share this common interest will be enhanced.

Finally, on behalf of Prof. Wang Daheng, Prof. Jin Guofan and Prof. Yu Xin, China Ordnance Society and Beijing Institute of Technology, I would like to heartily thank our sponsors and supporters for all they have done for this meeting. Thanks also to all the authors for their contribution to these proceedings; to all of the participants and friends for their interest and efforts in helping us to make this symposium possible, especially those who have traveled great distances and taken their valuable time from their very busy schedules to attend the meeting, to the advisory and organizing committees for their effective work and valuable advice; and to all the organizations and individuals concerned for their active support and assistance, especially the Editorial Office of Optical Technique for

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Liwei Zhou

Topical Committee of Optics, China Ordnance Society